SBR Technology

Roadmap of IC packaging materials to meet next-generation smartphone performance requirements

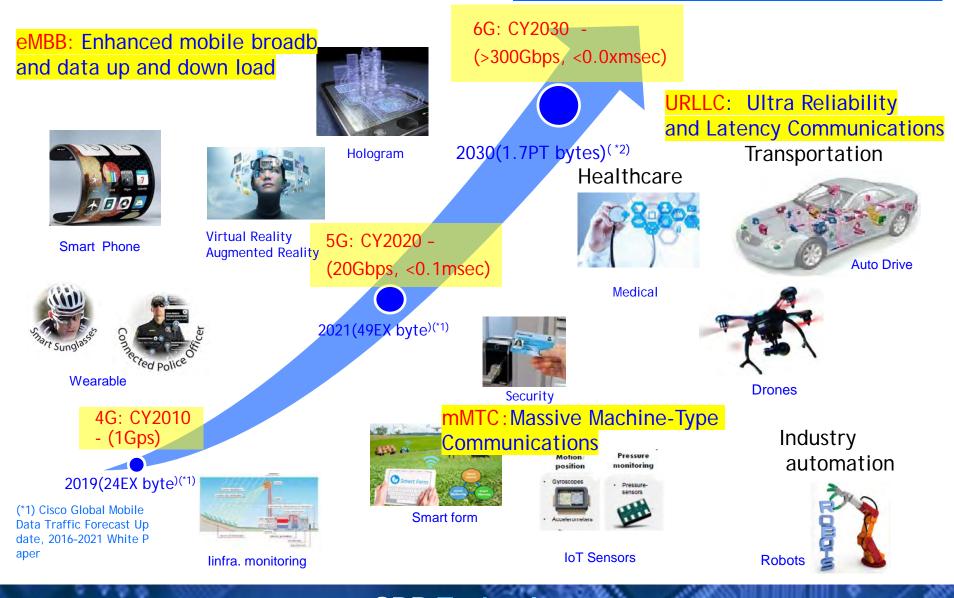
> May 30th 2019 rev01 SBR Technology Co., Ltd. Toshihiko Nishio

Heterogenous Integration toward 6G era

- Smartphone for eMBB and URLLC
 - Application processor
 - mmWave antenna
- To be covered detail roadmap by material leaders

5G to 6G performance trends

Semiconductor and package material companies has been focus toward 6G

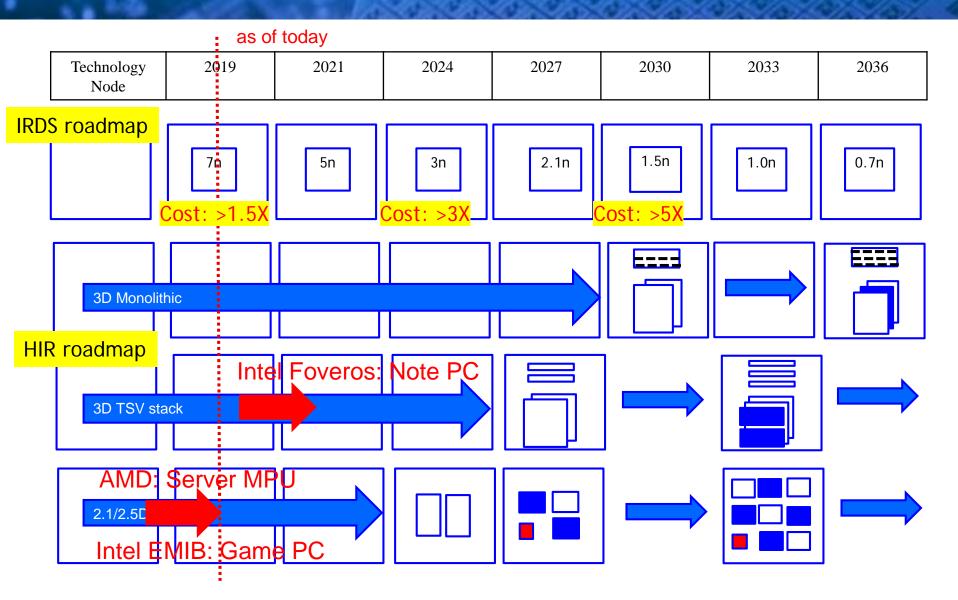


5G to 6G package technology trends

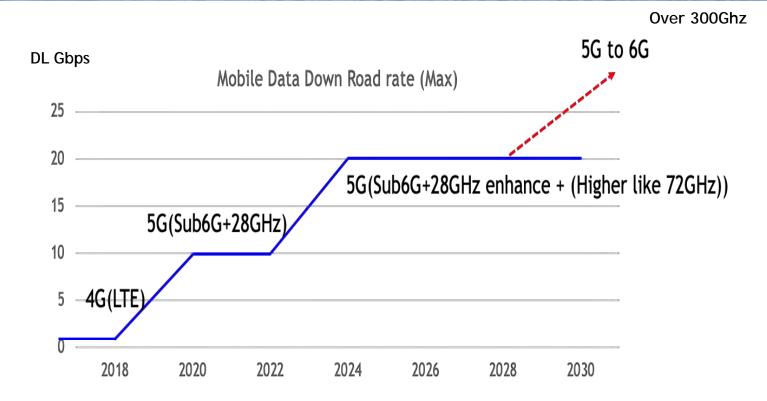
4



IRDS roadmap & Die partitioning



AP performance requirements toward 6G

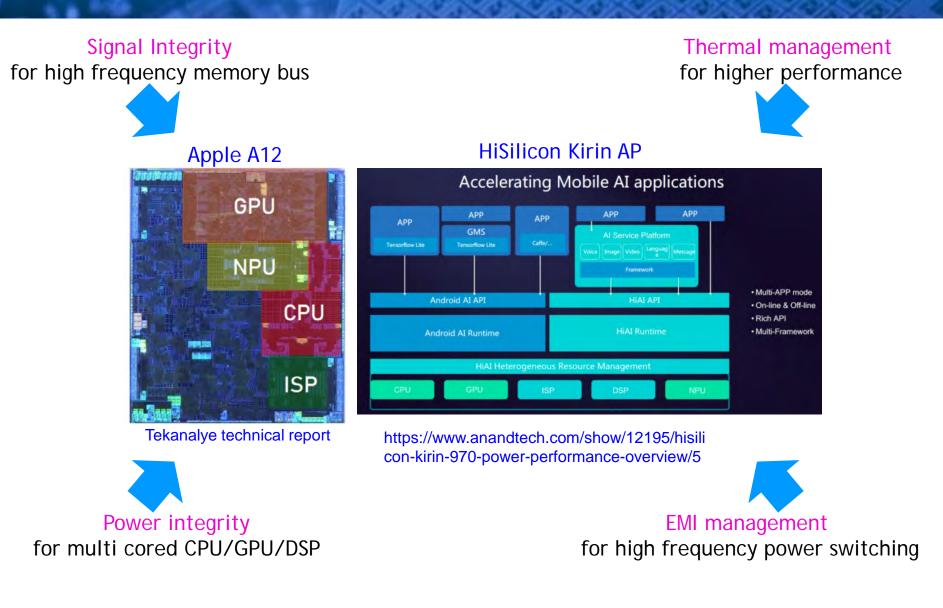


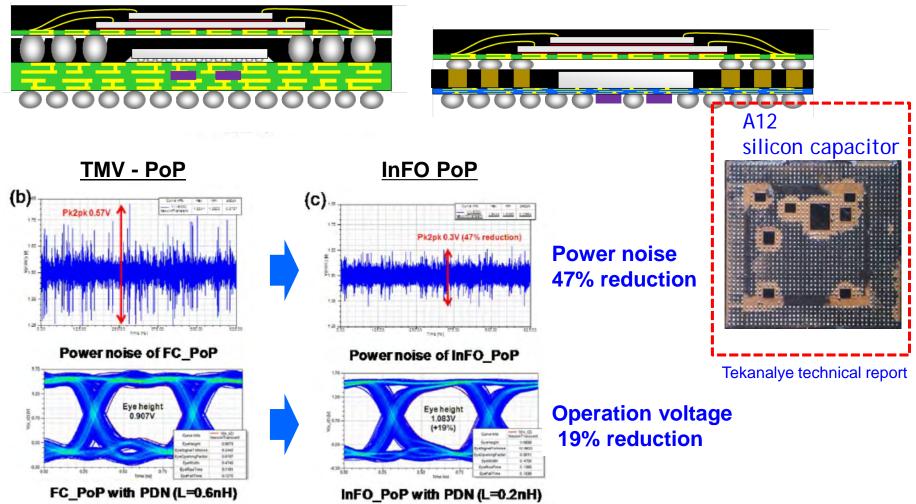
| | Production year | | | | | | | |
|--------------------------|-----------------|--------|--------|----------|---------|---------|--|--|
| | 2018 | 2021 | 2024 | 2027 | 2030 | 2033 | | |
| BB antenna performance | 1Gbps | 10Gbps | 20GBps | 20Gbps + | 100Gbps | 200Gbps | | |
| Data down load rate (*1) | 350Mbps | 1Gbps | 2Gbps | 3Gbps | 5Gbps | 10Gbps | | |

(*1): estimated max in smartphone

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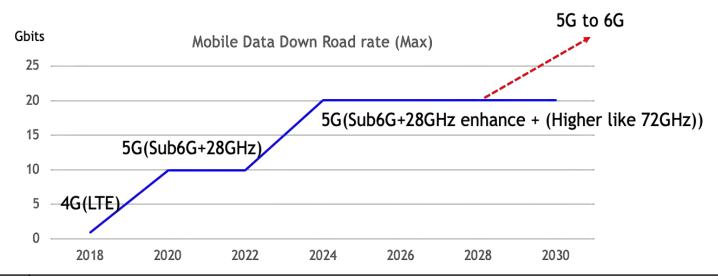
Package technology and design optimization for AI application processor





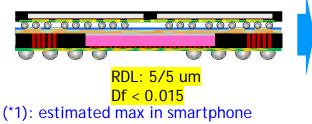
InFO (Wafer Level Integrated Fan-Out) Technology: Chien-Fu Tseng., etal, TSMC, ECTC 2016

AP performance requirements toward 6G

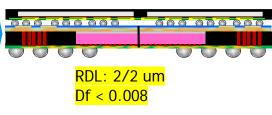


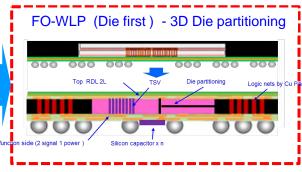
| | Production year | | | | | | | |
|--------------------------|-----------------|-------|-------|-------|-------|--------|--|--|
| | 2018 | 2021 | 2024 | 2027 | 2030 | 2033 | | |
| AP performance (index) | 1.00 | 1.75 | 2.66 | 4.05 | 6.15 | 9.36 | | |
| Data down load rate (*1) | 350Mbps | 1Gbps | 2Gbps | 3Gbps | 5Gbps | 10Gbps | | |

FO-WLP (Die first)



FO-WLP (Die first) - Die partitioning





Material requirements for AP package

Mold

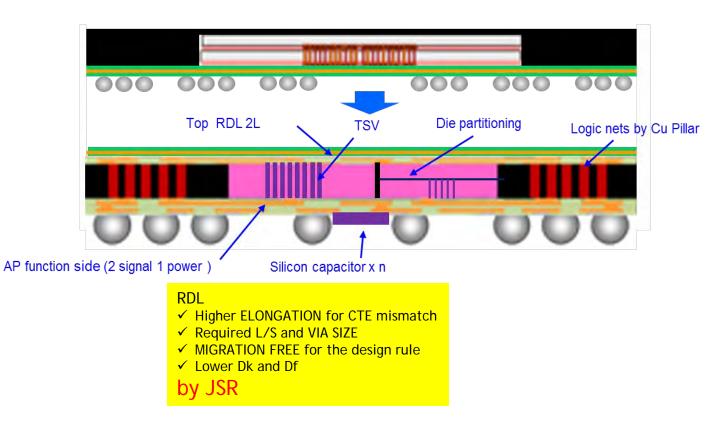
- ✓ Higher STIFFNESS with lower stress
- ✓ Higher ADHEISION with Silicon Dies
- ✓ Minimum VOLUME SHRINKAGE in curing process
- ✓ Lower THERMAL REGISTANCE

by Nagase

FO-PLP for Wide bus memory

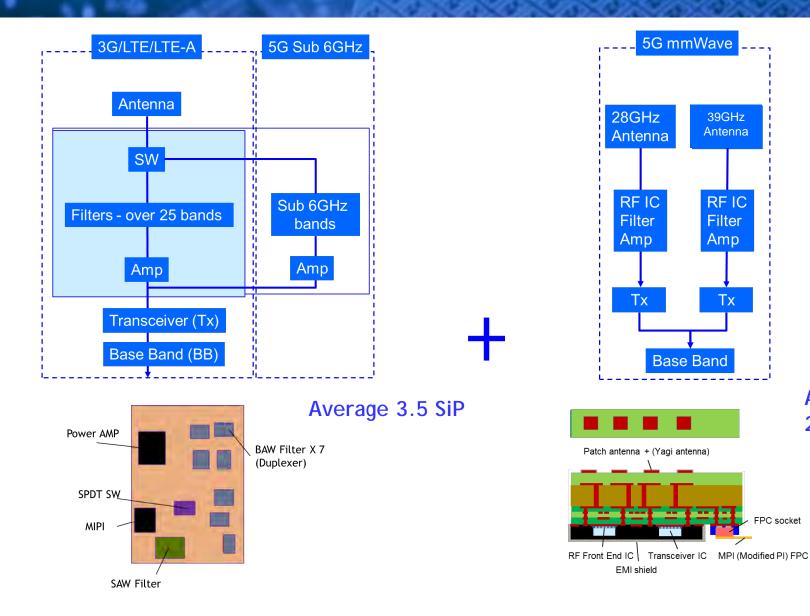
3D TSV

Higher yield TSV PROCESS Die to Die dense INTERCONNECTION High through put and reliable NCF Bond and De bond for temporally bonding



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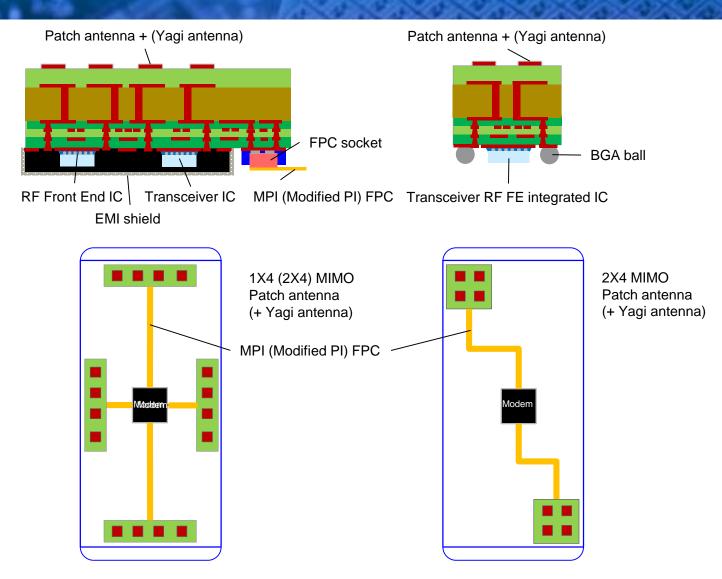
5G antenna and RF IC concept

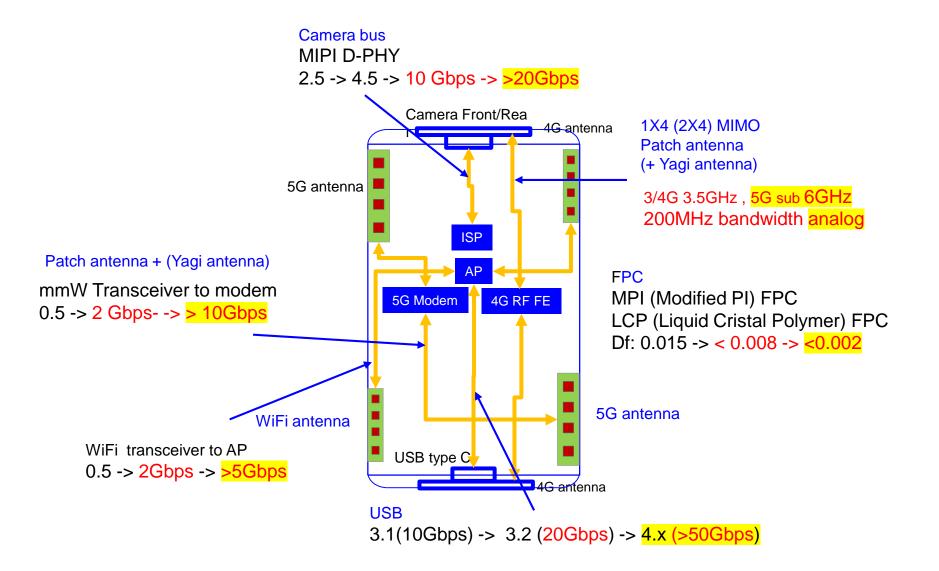


Additionally 2-4 SiP

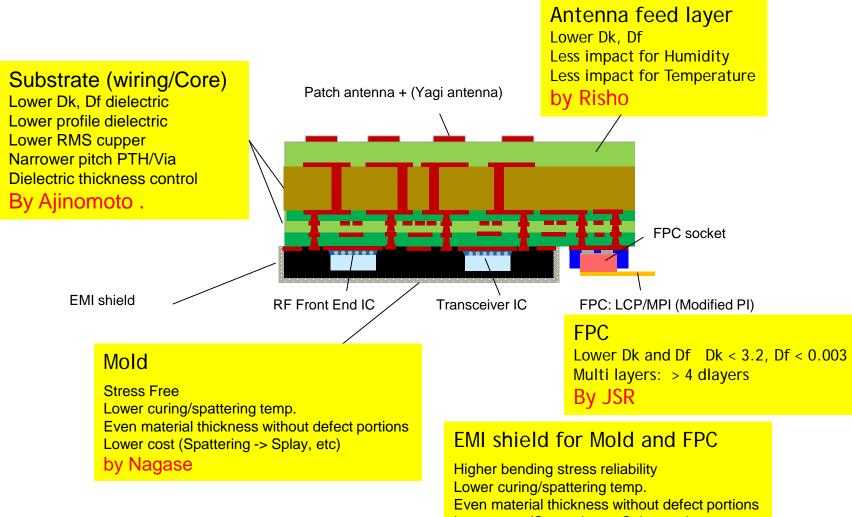
FPC socket

5G mm Wave AiP(Antenna in Package) concept





Material requirements for AiP



Lower cost (Spattering -> Splay, etc)

by Tatsuta

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Thanks for your attention !